VTB PROCESS BLUE ENHANCED, ULTRA HIGH DARK RESISTANCE

FEATURES

- Enhanced UV to IR spectral range
- Integral IR rejection filters available
- Response @ 220 nm, 0.06 A/W, typical with UV window
- Response @ 365 nm, 0.14 A/W typical
- High open circuit voltage @ low light levels
- 1 to 2% linearity over 7 to 9 decades
- Very low dark current & high shunt resistance

PRODUCT DESCRIPTION

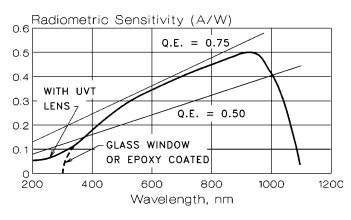
This series of P on N silicon planar photodiodes have been designed to maximize their response through the visible part of the spectrum. Those units with UV transmitting windows also exhibit excellent response in the UV region and are characterized at 220 nm.

"B" series devices have a built-in infrared rejection filter for those applications where a detector is needed that approximates the human eye. Typical transmission of wavelengths greater than 750 nm is less than 3% when measured with an incandescent source operating at 2850 K.

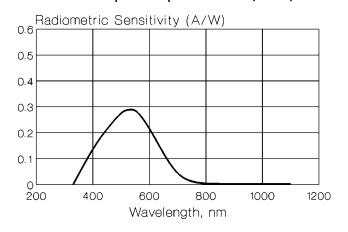
Diodes made with the VTB process are primarily intended for use in the photovoltaic mode but may be used with a small reverse bias. All photodiodes in this series exhibit very high shunt resistance. This characteristic leads to very low offsets when the diodes are used in high gain transimpedance op-amp circuits.

TYPICAL CHARACTERISTIC CURVES @ 25°C (UNLESS OTHERWISE NOTED)

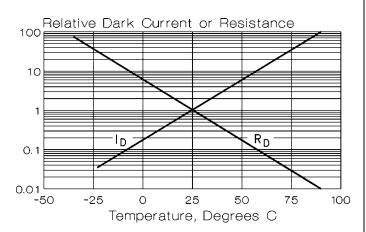
Absolute Spectral Response



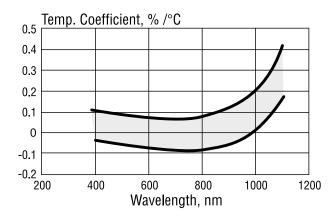
Absolute Spectral Response "B" Series (Filtered)



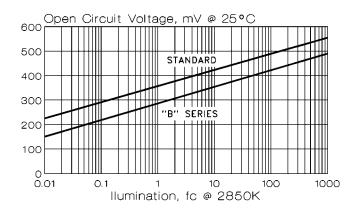
Relative Dark Current or Resistance vs. Temperature (Refered To 25°C)



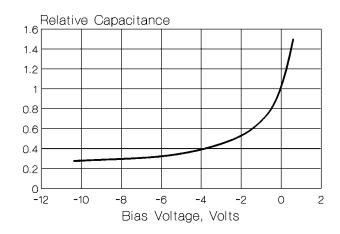
Temperature Coefficient of Light Current vs. Wavelength



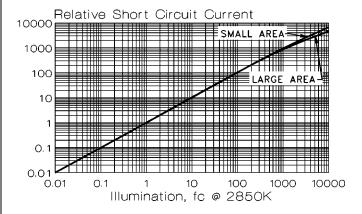
Open Circuit Voltage vs Illumination



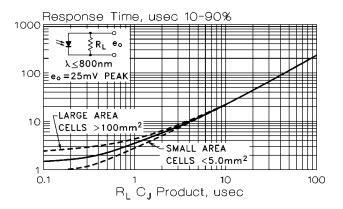
Relative Junction Capacitance vs. Voltage (Reffered To Zero Bias)



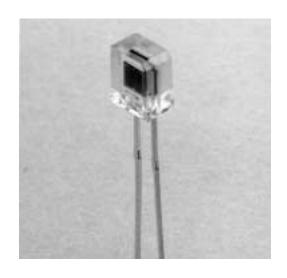
Relative Short Circuit Current vs. Illumination



Rise/fall Times - Non Standard



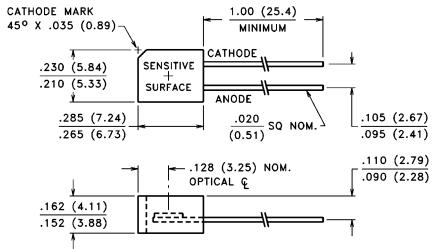
VTB100



PRODUCT DESCRIPTION

Planar silicon photodiode in a clear molded plastic sidelooker package suitable for assembly onto printed circuit boards. These diodes have very high shunt resistance and have good blue response.

PACKAGE DIMENSIONS inch (mm)



CASE 52 FLAT SIDELOOKER CHIP ACTIVE AREA: .012 in² (7.45 mm²)

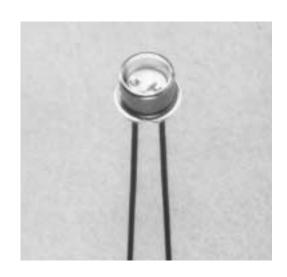
ABSOLUTE MAXIMUM RATINGS

Storage Temperature: -40°C to 100°C

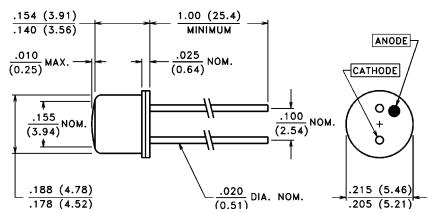
Operating Temperature: -40°C to 100°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS		VTB100		UNITS
STIVIDUL	CHARACTERISTIC	TEST CONDITIONS	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	50	65		μA
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.12	.23	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		490		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0		mV/°C
I _D	Dark Current	$H = 0$, $V_R = 10 V$		50	500	pA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		1.4		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0		%/°C
СЈ	Junction Capacitance	H = 0, V = 0			2.0	nF
S _R	Sensitivity	365 nm		.1		A/W
λ_{range}	Spectral Application Range		320		1100	nm
λ_{p}	Spectral Response - Peak			920		nm
V_{BR}	Breakdown Voltage		30	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±70		Degrees
NEP	Noise Equivalent Power			2.6 x 10 ⁻¹⁴ (Typ.)		W/√Hz
D*	Specific Detectivity			1.05 x 10 ¹³ (Typ.)		cm $\sqrt{Hz/W}$

VTB1012, 1013



PACKAGE DIMENSIONS inch (mm)



CASE 17 TO-46 HERMETIC CHIP ACTIVE AREA: .0025 in² (1.60 mm²)

PRODUCT DESCRIPTION

Small area planar silicon photodiode in a "flat" window, dual lead TO-46 package. Cathode is common to the case. These diodes have very high shunt resistance and have good blue response.

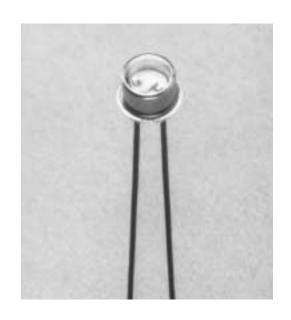
ABSOLUTE MAXIMUM RATINGS

Storage Temperature: -40°C to 110°C

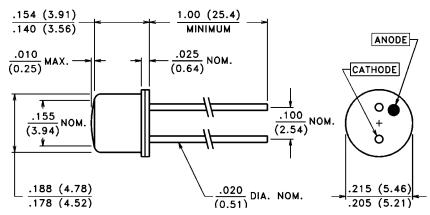
Operating Temperature: -40°C to 110°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS		VTB1012	2		VTB1013	}	UNITS
STIVIDUL	CHARACTERISTIC	TEST CONDITIONS	Min.	Тур.	Max.	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	8	13		8	13		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.12	.23		.12	.23	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		490			490		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0			-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			100			20	pA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.25			7.0		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = O, V = 10 mV		-8.0			-8.0		%/°C
СЈ	Junction Capacitance	H = 0, V = 0		.31			.31		nF
S _R	Sensitivity	365 nm		.09			.09		A/W
λrange	Spectral Application Range		320		1100	320		1100	nm
λр	Spectral Response - Peak			920			920		nm
V_{BR}	Breakdown Voltage		2	40		2	40		V
θ1/2	Angular Resp 50% Resp. Pt.			±35			±35		Degrees
NEP	Noise Equivalent Power		3.0 x 10 ⁻¹⁴ (Typ.)		5.9 x 10 ⁻¹⁵ (Typ.)			W∕√Hz	
D*	Specific Detectivity		4.2	x 10 ¹² (T	- ур.)	2.1	x 10 ¹³ (T	yp.)	cm√Hz/W

VTB1012B, 1013B



PACKAGE DIMENSIONS inch (mm)



CASE 17 TO-46 HERMETIC CHIP ACTIVE AREA: .0025 in² (1.60 mm²)

PRODUCT DESCRIPTION

Small area planar silicon photodiode in a "flat" window, dual lead TO-46 package. The package incorporates an infrared rejection filter. Cathode is common to the case. These diodes have very high shunt resistance and have good blue response.

ABSOLUTE MAXIMUM RATINGS

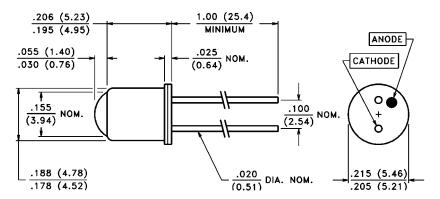
Storage Temperature: -40°C to 110°C
Operating Temperature: -40°C to 110°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS	'	/TB1012I	3	VTB1013B			UNITS
STIVIDUL	CHARACTERISTIC	TEST CONDITIONS	Min.	Тур.	Max.	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	0.8	1.3		0.8	1.3		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.02	.08		.02	.08	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		420			420		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0			-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			100			20	pA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.25			7.0		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0			-8.0		%/°C
СЛ	Junction Capacitance	H = 0, V = 0		.31			.31		nF
λ_{range}	Spectral Application Range		330		720	330		720	nm
λ_{p}	Spectral Response - Peak			580			580		nm
V_{BR}	Breakdown Voltage		2	40		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±35			±35		Degrees
NEP	Noise Equivalent Power		5.3 x 10 ⁻¹⁴ (Typ.)		1.1 x 10 ⁻¹⁴ (Typ.)			W∕√ Hz	
D*	Specific Detectivity		2.4	x 10 ¹² (T	yp.)	1.2	x 10 ¹³ (T	yp.)	cm√Hz/W

VTB1112, 1113



PACKAGE DIMENSIONS inch (mm)



CASE 19 TO-46 LENSED HERMETIC CHIP ACTIVE AREA: .0025 in² (1.60 mm²)

PRODUCT DESCRIPTION

Small area planar silicon photodiode in a lensed, dual lead TO-46 package. Cathode is common to the case. These diodes have very high shunt resistance and have good blue response.

ABSOLUTE MAXIMUM RATINGS

Storage Temperature: -40°C to 110°C

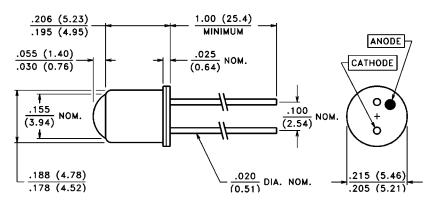
Operating Temperature: -40°C to 110°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS		VTB1112			VTB1113	}	- UNITS
STIVIDOL	CHARACTERISTIC	TEST CONDITIONS	Min.	Тур.	Max.	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	30	60		30	60		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.12	.23		.12	.23	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		490			490		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0			-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			100			20	pA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.25			7.0		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0			-8.0		%/°C
СЈ	Junction Capacitance	H = 0, V = 0		.31			.31		nF
S _R	Sensitivity	365 nm		.19			.19		A/W
λ_{range}	Spectral Application Range		320		1100	320		1100	nm
λ_{p}	Spectral Response - Peak			920			920		nm
V_{BR}	Breakdown Voltage		2	40		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±15			±15		Degrees
NEP	Noise Equivalent Power		3.0 x 10 ⁻¹⁴ (Typ.)		5.9 x 10 ⁻¹⁵ (Typ.)			W∕√ Hz	
D*	Specific Detectivity		4.2	x 10 ¹² (T	yp.)	2.1	x 10 ¹³ (T	yp.)	cm√Hz/W

VTB1112B, 1113B



PACKAGE DIMENSIONS inch (mm)



CASE 19 TO-46 LENSED HERMETIC CHIP ACTIVE AREA: .0025 in² (1.60 mm²)

PRODUCT DESCRIPTION

Small area planar silicon photodiode in a lensed, dual lead TO-46 package. The package incorporates an infrared rejection filter. Cathode is common to the case. These diodes have very high shunt resistance and have good blue response.

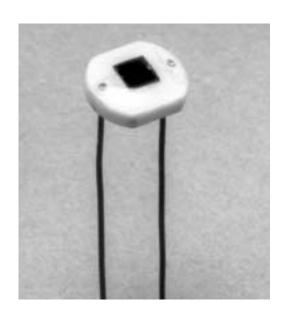
ABSOLUTE MAXIMUM RATINGS

Storage Temperature: -40°C to 110°C

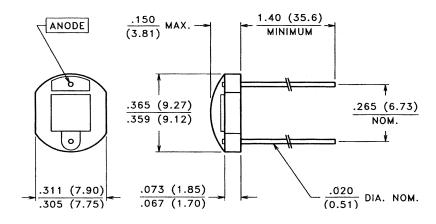
Operating Temperature: -40°C to 110°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS	'	/TB1112I	В	VTB1113B			UNITS
STIVIDUL	CHARACTERISTIC	TEST CONDITIONS	Min.	Тур.	Max.	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	3.0	6.0		3.0	6.0		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.02	.08		.02	.08	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		420			420		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0			-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			100			20	pA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.25			7.0		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0			-8.0		%/°C
СЈ	Junction Capacitance	H = 0, V = 0		.31			.31		nF
λ_{range}	Spectral Application Range		330		720	330		720	nm
λ_{p}	Spectral Response - Peak			580			580		nm
V _{BR}	Breakdown Voltage		2	40		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±15			±15		Degrees
NEP	Noise Equivalent Power		5.3 x 10 ⁻¹⁴ (Typ.)		1.1 x 10 ⁻¹⁴ (Typ.)			W∕√Hz	
D*	Specific Detectivity		2.4	x 10 ¹² (T	ур.)	1.2	x 10 ¹³ (T	yp.)	cm √Hz/W

VTB4051



PACKAGE DIMENSIONS inch (mm)



CASE 13 CERAMIC
CHIP ACTIVE AREA: .023 in² (14.8 mm²)

PRODUCT DESCRIPTION

Planar silicon photodiode mounted on a two lead ceramic substrate and coated with a layer of clear epoxy. These diodes have very high shunt resistance and have good blue response.

ABSOLUTE MAXIMUM RATINGS

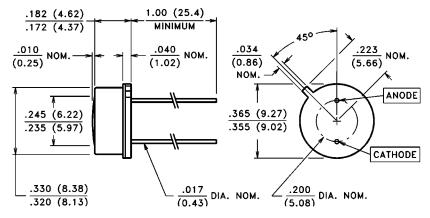
Storage Temperature: -20°C to 75°C Operating Temperature: -20°C to 75°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS		VTB4051		UNITS	
STIVIDUL	CHARACTERISTIC	TEST CONDITIONS	Min.	Тур.	Max.	UNITS	
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	100	200		μΑ	
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.12	.23	%/°C	
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		490		mV	
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0		mV/°C	
I _D	Dark Current	H = 0, VR = 2.0 V			250	pA	
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.56		$G\Omega$	
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0		%/°C	
СЈ	Junction Capacitance	H = 0, V = 0		3.0		nF	
S _R	Sensitivity	365 nm		.10		A/W	
λ_{range}	Spectral Application Range		320		1100	nm	
λ_{p}	Spectral Response - Peak			920		nm	
V_{BR}	Breakdown Voltage		2	40		V	
θ _{1/2}	Angular Resp 50% Resp. Pt.			±60 2.1 x 10 ⁻¹⁴ (Typ.)		Degrees	
NEP	Noise Equivalent Power			W∕√Hz			
D*	Specific Detectivity			1.8 x 10 ¹³ (Typ.)		cm√Hz/W	

VTB5051



PACKAGE DIMENSIONS inch (mm)



CASE 14 TO-5 HERMETIC CHIP ACTIVE AREA: .023 in² (14.8 mm²)

PRODUCT DESCRIPTION

Planar silicon photodiode in a "flat" window, dual lead TO-5 package. Cathode is common to the case. These diodes have very high shunt resistance and have good blue response.

ABSOLUTE MAXIMUM RATINGS

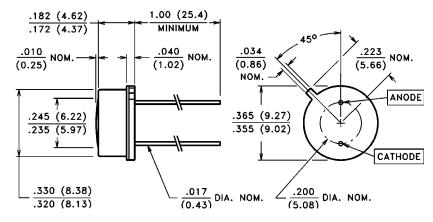
Storage Temperature: -40°C to 110°C
Operating Temperature: -40°C to 110°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS		VTB5051		UNITS
STIMBUL	CHARACTERISTIC	TEST CONDITIONS	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	85	130		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.12	.23	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		490		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			250	pA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.56		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0		%/°C
СЈ	Junction Capacitance	H = 0, V = 0		3.0		nF
S _R	Sensitivity	365 nm		.10		A/W
λ_{range}	Spectral Application Range		320		1100	nm
λ_{p}	Spectral Response - Peak			920		nm
V_{BR}	Breakdown Voltage		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±50		Degrees
NEP	Noise Equivalent Power			2.1 x 10 ⁻¹⁴ (Typ.)		W/√Hz
D*	Specific Detectivity			1.8 x 10 ¹³ (Typ.)		cm√Hz/W

VTB5051B



PACKAGE DIMENSIONS inch (mm)



CASE 14 TO-5 HERMETIC CHIP ACTIVE AREA: .023 in² (14.8 mm²)

PRODUCT DESCRIPTION

Planar silicon photodiode in a "flat" window, dual lead TO-5 package. The package incorporates an infrared rejection filter. Cathode is common to the case. These diodes have very high shunt resistance and have good blue response.

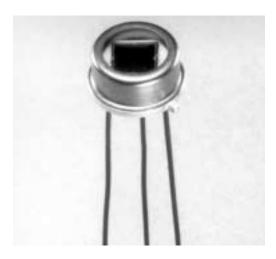
ABSOLUTE MAXIMUM RATINGS

Storage Temperature: -40°C to 110°C

Operating Temperature: -40°C to 110°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS		VTB5051B		UNITS	
STIVIDUL	CHARACTERISTIC	TEST CONDITIONS	Min.	Тур.	Max.	UNITS	
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	8	13		μΑ	
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.02	.08	%/°C	
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		420		mV	
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0		mV/°C	
I _D	Dark Current	H = 0, VR = 2.0 V			250	pA	
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.56		GΩ	
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0		%/°C	
СЛ	Junction Capacitance	H = 0, V = 0		3.0		nF	
λ_{range}	Spectral Application Range		330		720	nm	
λ_{p}	Spectral Response - Peak			580		nm	
V_{BR}	Breakdown Voltage		2	40		V	
θ _{1/2}	Angular Resp 50% Resp. Pt.			±50		Degrees	
NEP	Noise Equivalent Power			W∕√Hz			
D*	Specific Detectivity			1.0 x 10 ¹³ (Typ.)		cm√Hz/W	

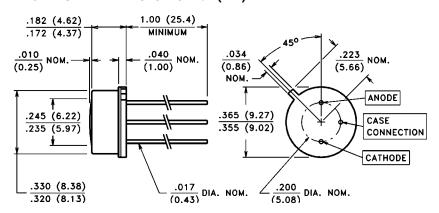
VTB5051J



PRODUCT DESCRIPTION

Planar silicon photodiode in a "flat" window, three lead TO-5 package. Chip is isolated from the case. The third lead allows the case to be grounded. These diodes have very high shunt resistance and have good blue response.

PACKAGE DIMENSIONS inch (mm)



CASE 14A TO-5 HERMETIC CHIP ACTIVE AREA: .023 in² (14.8 mm²)

ABSOLUTE MAXIMUM RATINGS

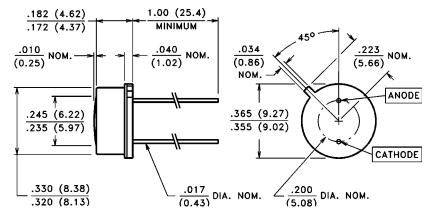
Storage Temperature: -40°C to 110°C
Operating Temperature: -40°C to 110°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS		VTB5051J		UNITS
STIMBUL	CHARACTERISTIC	TEST CONDITIONS	Min.	Тур.	Max.	UINITS
I_{SC}	Short Circuit Current	H = 100 fc, 2850 K	85	130		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.12	.23	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		490		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			250	pA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.56		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0		%/°C
CJ	Junction Capacitance	H = 0, V = 0		3.0		nF
S_R	Sensitivity	365 nm		.10		A/W
λ_{range}	Spectral Application Range		320		1100	nm
λ_{p}	Spectral Response - Peak			920		nm
V_{BR}	Breakdown Voltage		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±50		Degrees
NEP	Noise Equivalent Power			W∕√Hz		
D*	Specific Detectivity			1.8 x 10 ¹³ (Typ.)		cm√Hz/W

VTB5051UV



PACKAGE DIMENSIONS inch (mm)



CASE 14 TO-5 HERMETIC CHIP ACTIVE AREA: .023 in² (14.8 mm²)

PRODUCT DESCRIPTION

Planar silicon photodiode in a dual lead TO-5 package with a UV transmitting "flat" window. Chip is common to the case. These diodes have very high shunt resistance and have good blue response.

ABSOLUTE MAXIMUM RATINGS

Storage Temperature: -40°C to 110°C

Operating Temperature: -40°C to 110°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS		VTB5051UV		UNITS
STIVIDUL	CHARACTERISTIC	TEST CONDITIONS	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	85	130		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.12	.23	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		490		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			250	pA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.56		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0		%/°C
СЈ	Junction Capacitance	H = 0, V = 0		3.0		nF
S _R	Sensitivity	365 nm		0.1		A/W
S _R	Sensitivity	220 nm	.038			A/W
λ_{range}	Spectral Application Range		200		1100	nm
$\lambda_{\rm p}$	Spectral Response - Peak			920		nm
V_{BR}	Breakdown Voltage		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±50		Degrees
NEP	Noise Equivalent Power			2.1 x 10 ⁻¹⁴ (Typ.)		W∕√ Hz
D*	Specific Detectivity			1.8 x 10 ¹³ (Typ.)		cm√Hz/W

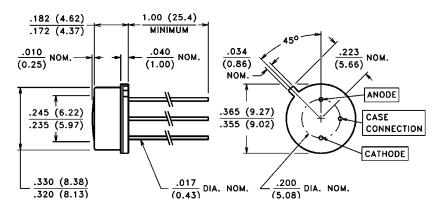
VTB5051UVJ



PRODUCT DESCRIPTION

Planar silicon photodiode in a three lead TO-5 package with a UV transmitting "flat" window. Chip is isolated from the case. The third lead allows case to be grounded. These diodes have very high shunt resistance and have good blue response.

PACKAGE DIMENSIONS inch (mm)



CASE 14A TO-5 HERMETIC
CHIP ACTIVE AREA: .023 in² (14.8 mm²)

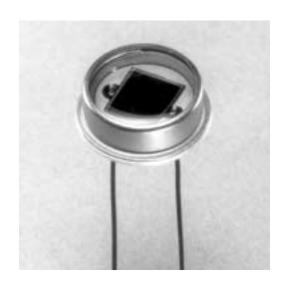
ABSOLUTE MAXIMUM RATINGS

Storage Temperature: -40°C to 110°C

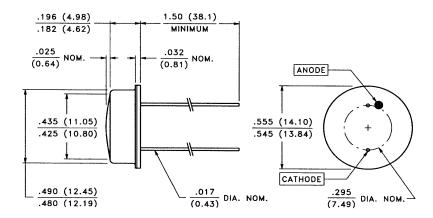
Operating Temperature: -40°C to 110°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS		VTB5051UVJ		UNITS
STIMBUL	CHARACTERISTIC	TEST CONDITIONS	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	85	130		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.12	.23	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		490		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			250	pA
R _{SH}	Shunt Resistance	H = 0, V = -10 mV		.56		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = -10 mV		-8.0		%/°C
СЈ	Junction Capacitance	H = 0, V = 0		3.0		nF
S _R	Sensitivity	365 nm		0.1		A/W
S _R	Sensitivity	220 nm	.038			A/W
$\lambda_{ m range}$	Spectral Application Range		200		1100	nm
λ_{p}	Spectral Response - Peak			920		nm
V _{BR}	Breakdown Voltage		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±50		Degrees
NEP	Noise Equivalent Power			W∕√Hz		
D*	Specific Detectivity			1.8 x 10 ¹³ (Typ.)		cm√Hz/W

VTB6061



PACKAGE DIMENSIONS inch (mm)



CASE 15 TO-8 HERMETIC CHIP ACTIVE AREA: .058 in² (37.7 mm²)

PRODUCT DESCRIPTION

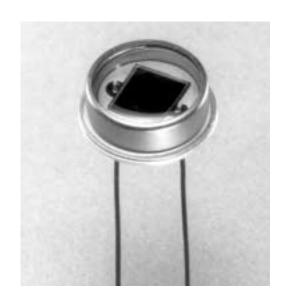
Large area planar silicon photodiode in a "flat" window, dual lead TO-8 package. Cathode is common to the case. These diodes have very high shunt resistance and have good blue response.

ABSOLUTE MAXIMUM RATINGS

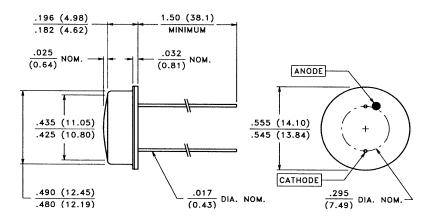
Storage Temperature: -40°C to 110°C
Operating Temperature: -40°C to 110°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS		VTB6061		UNITS
STIMBUL	CHARACTERISTIC	TEST CONDITIONS	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	260	350		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.12	.23	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		490		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			2.0	pA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.10		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0		%/°C
СЈ	Junction Capacitance	H = 0, V = 0		8.0		nF
S_R	Sensitivity	365 nm		0.1		A/W
λ_{range}	Spectral Application Range		320		1100	nm
λ_{p}	Spectral Response - Peak			920		nm
V_{BR}	Breakdown Voltage		2	40		٧
θ _{1/2}	Angular Resp 50% Resp. Pt.			±55		Degrees
NEP	Noise Equivalent Power			W∕√Hz		
D*	Specific Detectivity			1.1 x 10 ¹³ (Typ.)		cm√Hz/W

VTB6061B



PACKAGE DIMENSIONS inch (mm)



CASE 15 TO-8 HERMETIC CHIP ACTIVE AREA: .058 in² (37.7 mm²)

PRODUCT DESCRIPTION

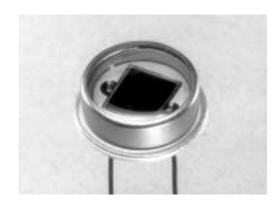
Large area planar silicon photodiode in a "flat" window, dual lead TO-8 package. The package incorporates an infrared rejection filter. Cathode is common to the case. These diodes have very high shunt resistance and have good blue response.

ABSOLUTE MAXIMUM RATINGS

Storage Temperature: -40°C to 110°C
Operating Temperature: -40°C to 110°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS -			UNITS	
STIVIDUL		TEST CONDITIONS	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	26	35		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.02	.08	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		420		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			2.0	nA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.10		$G\Omega$
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0		%/°C
СЛ	Junction Capacitance	H = 0, V = 0		8.0		nF
λ_{range}	Spectral Application Range		330		720	nm
λ_{p}	Spectral Response - Peak			580		nm
V_{BR}	Breakdown Voltage		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±55 1.0 x 10 ⁻¹³ (Typ.)		Degrees
NEP	Noise Equivalent Power			W∕√Hz		
D*	Specific Detectivity			6.1 x 10 ¹² (Typ.)		cm√Hz/W

VTB6061CIE



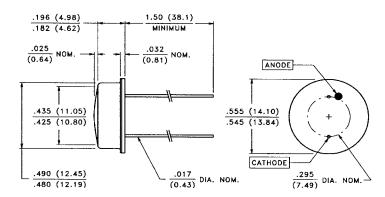
PRODUCT DESCRIPTION

Large area planar silicon photodiode in a "flat" window, dual lead TO-8 package. This photodiode is a spectrally modified VTB6061B with a spectral response closely resembling that of the human eye, making it an ideal choice for photometric calibrations. Its high shunt impedance permits accurate measurement of low illuminations.

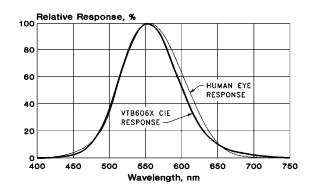
ABSOLUTE MAXIMUM RATINGS

Storage Temperature: -55°C to 50°C Operating Temperature: -55°C to 50°C

PACKAGE DIMENSIONS inch (mm)

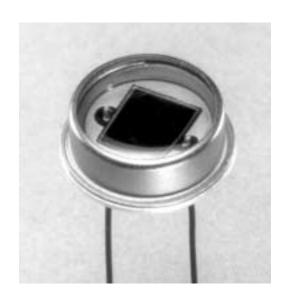


CASE 15 TO-8 HERMETIC
CHIP ACTIVE AREA: .058 in² (37.7 mm²)
VTB6061CIE vs HUMAN EYE RESPONSE

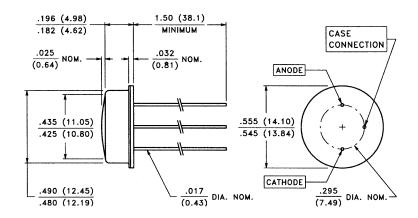


SYMBOL	CHARACTERISTIC	TEST CONDITIONS -		UNITS		
STWIDOL	CHARACTERISTIC		Min.	Тур.	Max.	UNITS
c	Photometric Sensitivity	H = 1.0 fc	75	120		nA/fc
S _P		H = 1.0 lux	7	11		nA/lux
R _{SH}	Shunt Resistance	H = 0, V -10 mV		.10		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V -10 mV		-8.0		%/°C
I _D	Dark Current	H = 0, VR = 2.0 V			2.0	nA
СЈ	Junction Capacitance	H = 0, V = 0		8.0	11	nF
λ_{p}	Spectral Response - Peak			555		nm
θ _{1/2}	Angular Resp 50% Resp. Pt.			±55		Degrees
NEP	Noise Equivalent Power			1.3 x 10 ⁻¹³ (Typ.)		W∕√Hz

VTB6061J



PACKAGE DIMENSIONS inch (mm)



CASE 15 TO-8 HERMETIC CHIP ACTIVE AREA: .058 in² (37.7 mm²)

PRODUCT DESCRIPTION

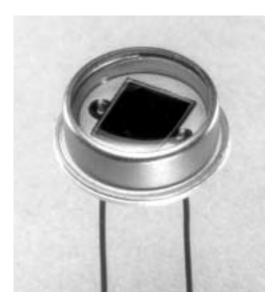
Large area planar silicon photodiode in a "flat" window, three lead TO-8 package. Chip is isolated from case. The third lead allows case to be grounded. These diodes have very high shunt resistance and have good blue response.

ABSOLUTE MAXIMUM RATINGS

Storage Temperature: -40°C to 110°C
Operating Temperature: -40°C to 110°C

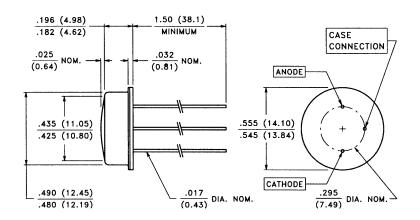
SYMBOL	CHARACTERISTIC TE	TEST CONDITIONS			- UNITS	
STIVIDUL		TEST CONDITIONS	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	260	350		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.12	.23	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		490		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			2.0	nA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.10		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0		%/°C
СЈ	Junction Capacitance	H = 0, V = 0		8.0		nF
S_R	Sensitivity	365 nm		0.1		A/W
λ_{range}	Spectral Application Range		320		1100	nm
λ_{p}	Spectral Response - Peak			920		nm
V_{BR}	Breakdown Voltage		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±55 5.7 x 10 ⁻¹⁴ (Typ.)		Degrees
NEP	Noise Equivalent Power			W∕√Hz		
D*	Specific Detectivity			1.1 x 10 ¹³ (Typ.)		cm√Hz/W

VTB6061UV



Large area planar silicon photodiode in a dual lead TO-8 package with a UV transmitting "flat" window. Cathode is common to the case. These diodes have very high shunt resistance and have good blue response.

PACKAGE DIMENSIONS inch (mm)



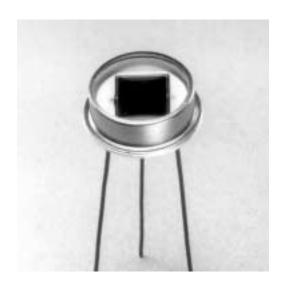
CASE 15 TO-8 HERMETIC CHIP ACTIVE AREA: .058 in² (37.7 mm²)

ABSOLUTE MAXIMUM RATINGS

Storage Temperature: -40°C to 110°C
Operating Temperature: -40°C to 110°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS		- UNITS		
STIMBUL		TEST CONDITIONS	Min.	Тур.	Max.	- UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	260	350		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.12	.23	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		490		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			2.0	nA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.10		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0		%/°C
СЈ	Junction Capacitance	H = 0, V = 0		8.0		nF
S_R	Sensitivity	365 nm		.10		A/W
S_R	Sensitivity	220 nm	.04			A/W
λ_{range}	Spectral Application Range		200		1100	nm
λ_{p}	Spectral Response - Peak			920		nm
V_{BR}	Breakdown Voltage		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±55		Degrees
NEP	Noise Equivalent Power			W∕√Hz		
D*	Specific Detectivity			1.1 x 10 ¹³ (Typ.)		cm√Hz/W

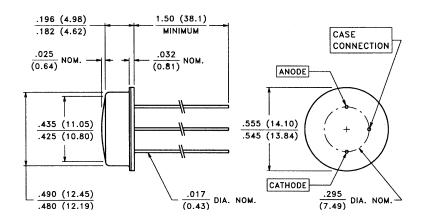
VTB6061UVJ



PRODUCT DESCRIPTION

Large area planar silicon photodiode in a three lead TO-8 package with a UV transmitting window. Chip is isolated from case. Third lead is grounded to case. These diodes have very high shunt resistance and have good blue response.

PACKAGE DIMENSIONS inch (mm)



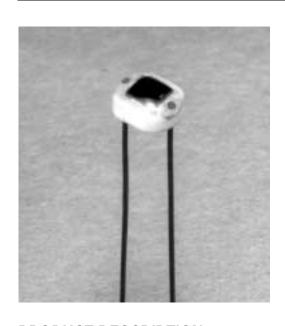
CASE 15A TO-8 HERMETIC CHIP ACTIVE AREA: .058 in² (37.7 mm²)

ABSOLUTE MAXIMUM RATINGS

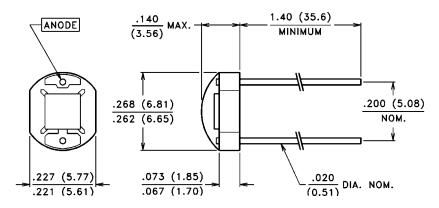
Storage Temperature: -40°C to 110°C
Operating Temperature: -40°C to 110°C

SYMBOL	CHARACTERISTIC TEST CON	TEST CONDITIONS		VTB6061UVJ	UNITS	
SYMBOL		TEST CONDITIONS	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	260	350		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.12	.23	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		490		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			2.0	nA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.10		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0		%/°C
СЛ	Junction Capacitance	H = 0, V = 0		8.0		nF
S _R	Sensitivity	365 nm		.10		A/W
S_R	Sensitivity	220 nm	.04			A/W
λ_{range}	Spectral Application Range		200		1100	nm
λ_{p}	Spectral Response - Peak			920		nm
V_{BR}	Breakdown Voltage		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±55		Degrees
NEP	Noise Equivalent Power			W∕√Hz		
D*	Specific Detectivity			1.1 x 10 ¹³ (Typ.)		cm√Hz/W

VTB8341



PACKAGE DIMENSIONS inch (mm)



CASE 11 CERAMIC
CHIP ACTIVE AREA: .008 in² (5.16 mm²)

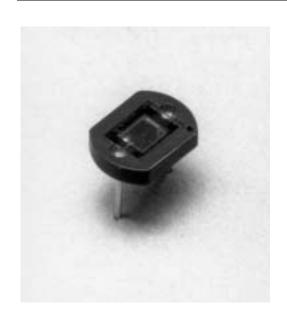
PRODUCT DESCRIPTION

Planar silicon photodiode mounted on a two lead ceramic substrate and coated with a thick layer of clear epoxy. These diodes have very high shunt resistance and have good blue response.

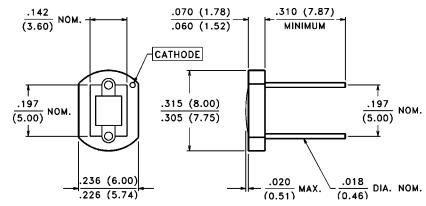
ABSOLUTE MAXIMUM RATINGS

Storage Temperature: -20°C to 75°C
Operating Temperature: -20°C to 75°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS		UNITS		
STIVIDUL	CHARACTERISTIC	TEST CONDITIONS	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	35	60		μA
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.12	.23	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		490		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			100	pA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		1.4		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0		%/°C
СЈ	Junction Capacitance	H = 0, V = 0		1.0		nF
S _R	Sensitivity	365 nm		.10		A/W
λ_{range}	Spectral Application Range		320		1100	nm
λ_{p}	Spectral Response - Peak			920		nm
V_{BR}	Breakdown Voltage		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±60		Degrees
NEP	Noise Equivalent Power			W∕√Hz		
D*	Specific Detectivity			cm√Hz/W		



PACKAGE DIMENSIONS inch (mm)



CASE 21 8 mm CERAMIC CHIP ACTIVE AREA: .008 in² (5.16 mm²)

PRODUCT DESCRIPTION

Planar silicon photodiode in a recessed ceramic package. Chip is coated with a protective layer of epoxy. These diodes have very high shunt resistance and have good blue response.

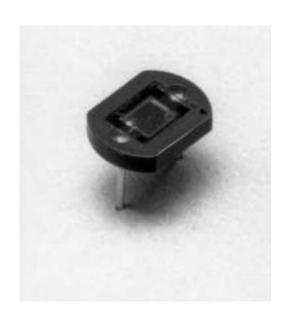
ABSOLUTE MAXIMUM RATINGS

Storage Temperature: -20°C to 75°C

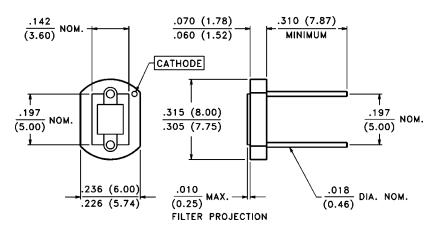
Operating Temperature: -20°C to 75°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS		VTB8440)	VTB8441			UNITS
STIVIDUL	CHARACTERISTIC	TEST CONDITIONS	Min.	Тур.	Max.	Min.	Тур.	Max.	UNITS
I_{SC}	Short Circuit Current	H = 100 fc, 2850 K	35	45		35	45		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.12	.23		.12	.23	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		490			490		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0			-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			2000			100	рА
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.07			1.4		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0			-8.0		%/°C
СЈ	Junction Capacitance	H = 0, V = 0		1.0			1.0		nF
S _R	Sensitivity	365 nm		.10			.10		A/W
λ_{range}	Spectral Application Range		320		1100	320		1100	nm
λ_{p}	Spectral Response - Peak			920			920		nm
V_{BR}	Breakdown Voltage		2	40		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±50			±50		Degrees
NEP	Noise Equivalent Power		5.9 x 10 ⁻¹⁴ (Typ.)		1.3 x 10 ⁻¹⁴ (Typ.)			W∕√Hz	
D*	Specific Detectivity		3.9	x 10 ¹² (T	ӯр.)	1.7	x 10 ¹³ (T	yp.)	cm√Hz/W

VTB8440B, 8441B



PACKAGE DIMENSIONS inch (mm)



CASE 21F 8 mm CERAMIC CHIP ACTIVE AREA: .008 in² (5.16 mm²)

PRODUCT DESCRIPTION

Planar silicon photodiode in recessed ceramic package. The package incorporates an infrared rejection filter. These diodes have very high shunt resistance and have good blue response.

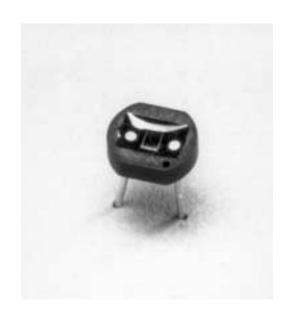
ABSOLUTE MAXIMUM RATINGS

Storage Temperature: -20°C to 75°C

Operating Temperature: -20°C to 75°C

SYMBOL	CHARACTERISTIC TEST CONDITIONS	'	VTB8440B			/TB8441I	UNITS		
STIMBUL		TEST CONDITIONS	Min.	Тур.	Max.	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	4	5		4	5		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.02	.08		.02	.08	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		420			420		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0			-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			2000			100	pA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.07			1.4		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0			-8.0		%/°C
СЈ	Junction Capacitance	H = 0, V = 0		1.0			1.0		nF
λ_{range}	Spectral Application Range		330		720	330		720	nm
λ_{p}	Spectral Response - Peak			580			580		nm
V_{BR}	Breakdown Voltage		2	40		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±50			±50		Degrees
NEP	Noise Equivalent Power		1.1 x 10 ⁻¹³ (Typ.)		2.4 x 10 ⁻¹⁴ (Typ.)			W∕√Hz	
D*	Specific Detectivity		2.2	x 10 ¹² (T	yp.)	9.7	x 10 ¹² (T	yp.)	cm√Hz/W

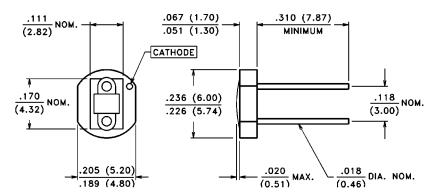
VTB9412, 9413



PRODUCT DESCRIPTION

Small area planar silicon photodiode in a recessed ceramic package. The chip is coated with a protective layer of clear epoxy. These diodes have very high shunt resistance and have good blue response.

PACKAGE DIMENSIONS inch (mm)



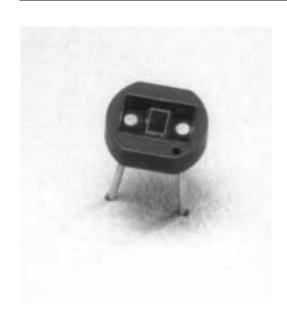
 $\begin{array}{ccc} \text{CASE 20} & \text{6 mm CERAMIC} \\ \text{CHIP ACTIVE AREA: .0025 in}^2 \text{ (1.60 mm}^2 \text{)} \end{array}$

ABSOLUTE MAXIMUM RATINGS

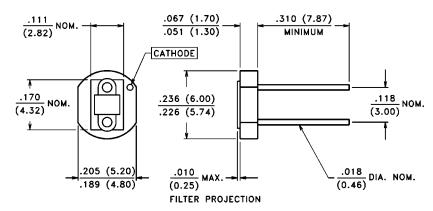
Storage Temperature: -20°C to 75°C Operating Temperature: -20°C to 75°C

SYMBOL	CHARACTERISTIC	TEST CONDITIONS		VTB9412	2		VTB9413	3	- UNITS
STIMBUL	CHARACTERISTIC	TEST CONDITIONS	Min.	Тур.	Max.	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	8	13		8	13		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.12	.23		.12	.23	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		490			490		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0			-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			100			20	pA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.25			7.0		$G\Omega$
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0			-8.0		%/°C
СЈ	Junction Capacitance	H = 0, V = 0		.31			.31		nF
S _R	Sensitivity	365 nm		.09			.09		A/W
$\lambda_{ m range}$	Spectral Application Range		320		1100	320		1100	nm
λ_{p}	Spectral Response - Peak			920			920		nm
V_{BR}	Breakdown Voltage		2	40		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±50			±50		Degrees
NEP	Noise Equivalent Power		3.0 x 10 ⁻¹⁴ (Typ.)		5.9 x 10 ⁻¹⁵ (Typ.)			W∕√Hz	
D*	Specific Detectivity		4.2	х 10 ¹² (Т	у р.)	2.1	x 10 ¹³ (T	yp.)	cm√Hz/W

VTB9412B, 9413B



PACKAGE DIMENSIONS inch (mm)



CASE 20F 6 mm CERAMIC CHIP ACTIVE AREA: .0025 in² (1.60 mm²)

PRODUCT DESCRIPTION

Small area planar silicon photodiode in a recessed ceramic package. The package incorporates an infrared rejection filter. These diodes have very high shunt resistance and have good blue response.

ABSOLUTE MAXIMUM RATINGS

Storage Temperature: -20°C to 75°C

Operating Temperature: -20°C to 75°C

SYMBOL	CHARACTERISTIC TEST CONDITIONS	VTB9412B			VTB9413B			UNITS	
STIMBUL		TEST CONDITIONS	Min.	Тур.	Max.	Min.	Тур.	Max.	UNITS
I _{SC}	Short Circuit Current	H = 100 fc, 2850 K	.8	1.3		.8	1.3		μΑ
TC I _{SC}	I _{SC} Temperature Coefficient	2850 K		.02	.08		.02	.08	%/°C
V _{OC}	Open Circuit Voltage	H = 100 fc, 2850 K		420			420		mV
TC V _{OC}	V _{OC} Temperature Coefficient	2850 K		-2.0			-2.0		mV/°C
I _D	Dark Current	H = 0, VR = 2.0 V			100			20	pA
R _{SH}	Shunt Resistance	H = 0, V = 10 mV		.25			7.0		GΩ
TC R _{SH}	R _{SH} Temperature Coefficient	H = 0, V = 10 mV		-8.0			-8.0		%/°C
СЈ	Junction Capacitance	H = 0, V = 0		.31			.31		nF
λ_{range}	Spectral Application Range		330		720	330		720	nm
λ_{p}	Spectral Response - Peak			580			580		nm
V_{BR}	Breakdown Voltage		2	40		2	40		V
θ _{1/2}	Angular Resp 50% Resp. Pt.			±50			±50		Degrees
NEP	Noise Equivalent Power		5.3 x 10 ⁻¹⁴ (Typ.)		1.1 x 10 ⁻¹⁴ (Typ.)			W∕√Hz	
D*	Specific Detectivity		2.4	x 10 ¹² (T	- ур.)	1.2	x 10 ¹³ (T	yp.)	cm√Hz/W